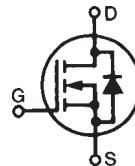


PolarHV™ HiPerFET Power MOSFET

N-Channel Enhancement Mode
Avalanche Rated
Fast Intrinsic Diode

IXFH 36N60P
IXFK 36N60P
IXFT 36N60P

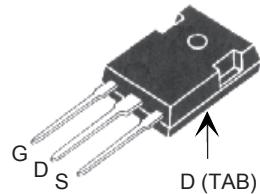
V_{DSS} = 600 V
I_{D25} = 36 A
R_{DS(on)} ≤ 190 mΩ
t_{rr} ≤ 200 ns



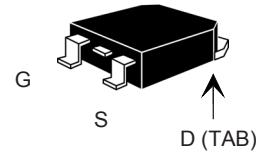
Symbol	Test Conditions	Maximum Ratings		
V _{DSS}	T _J = 25°C to 150°C	600	V	
V _{DGR}	T _J = 25°C to 150°C; R _{GS} = 1 MΩ	600	V	
V _{GSS}	Continuous	±30	V	
V _{GSM}	Transient	±40	V	
I _{D25}	T _C = 25°C	36	A	
I _{DM}	T _C = 25°C, pulse width limited by T _{JM}	80	A	
I _{AR}	T _C = 25°C	36	A	
E _{AR}	T _C = 25°C	50	mJ	
E _{AS}	T _C = 25°C	1.5	J	
dv/dt	I _S ≤ I _{DM} , di/dt ≤ 100 A/μs, V _{DD} ≤ V _{DSS} , T _J ≤ 150°C, R _G = 4 Ω	20	V/ns	
P _D	T _C = 25°C	650	W	
T _J		-55 ... +150	°C	
T _{JM}		150	°C	
T _{stg}		-55 ... +150	°C	
M _d	Mounting torque (TO-247 & TO-264)	1.13/10	Nm/lb.in.	
Weight	TO-247	6	g	
	TO-268	5	g	
	TO-264	10	g	
T _L	1.6 mm (0.062 in.) from case for 10 s	300	°C	
T _{SOLD}	Plastic body for 10 s	260	°C	

Symbol	Test Conditions (T _J = 25°C, unless otherwise specified)	Characteristic Values		
		Min.	Typ.	Max.
BV _{DSS}	V _{GS} = 0 V, I _D = 250 μA	600		V
V _{GS(th)}	V _{DS} = V _{GS} , I _D = 4 mA	3.0	5.0	V
I _{GSS}	V _{GS} = ±30 V _{DC} , V _{DS} = 0		±200	nA
I _{DSS}	V _{DS} = V _{DSS} V _{GS} = 0 V	T _J = 125°C	100 1000	μA
R _{DS(on)}	V _{GS} = 10 V, I _D = 0.5 I _{D25} Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		190	mΩ

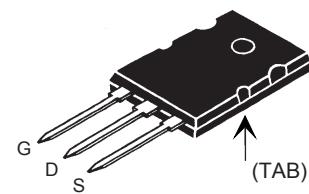
TO-247 (IXFH)



TO-268 (IXFT) Case Style



TO-264 AA (IXFK)



G = Gate D = Drain
S = Source Tab = Drain

Features

- International standard packages
- Fast recovery diode
- Unclamped Inductive Switching (UIS) rated
- Low package inductance
 - easy to drive and to protect

Advantages

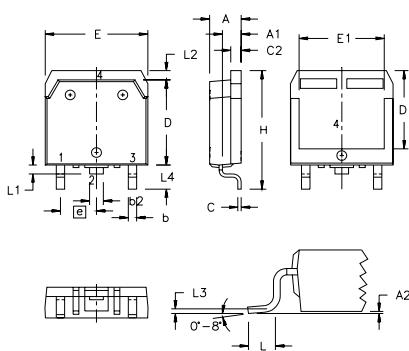
- Easy to mount
- Space savings
- High power density

Symbol **Test Conditions**
Characteristic Values
 $(T_J = 25^\circ C, \text{ unless otherwise specified})$
Min. **Typ.** **Max.**

g_{fs}	$V_{DS} = 20 V; I_D = 0.5 I_{D25}$, pulse test	25	39	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 V, V_{DS} = 25 V, f = 1 \text{ MHz}$	5800	pF	
		570	pF	
		30	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 V, V_{DS} = 0.5 I_{D25}$ $R_G = 2 \Omega$ (External)	30	ns	
		25	ns	
		80	ns	
		22	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 V, V_{DS} = 0.5 V_{DSS}, I_D = 0.5 I_{D25}$	102	nC	
		34	nC	
		36	nC	
R_{thJC}			0.19	°C/W
R_{thCS}	TO-247	0.21		°C/W
R_{thCS}	TO-264	0.15		°C/W

Source-Drain Diode
Characteristic Values
 $(T_J = 25^\circ C, \text{ unless otherwise specified})$
Symbol **Test Conditions**
Min. **Typ.** **Max.**

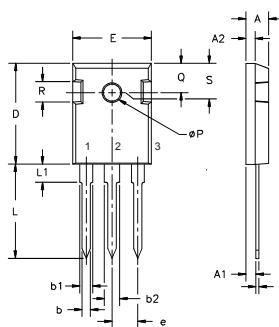
I_s	$V_{GS} = 0 V$		36	A
I_{SM}	Repetitive		80	A
V_{SD}	$I_F = I_s, V_{GS} = 0 V,$ Pulse test, $t \leq 300 \mu s$, duty cycle $d \leq 2\%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = 25 A, -di/dt = 100 A/\mu s$ $V_R = 100 V$	200	ns	
		0.8	μC	
		6.0	A	

TO-268 (IXFT) Outline


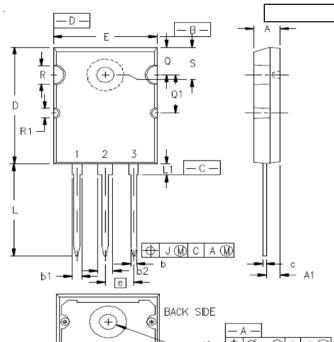
SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.193	.201	4.90	5.10
A1	.106	.114	2.70	2.90
A2	.001	.010	0.02	0.25
b	.045	.057	1.15	1.45
b2	.075	.083	1.90	2.10
C	.016	.026	0.40	0.65
C2	.057	.063	1.45	1.60
D	.543	.551	13.80	14.00
D1	.488	.500	12.40	12.70
E	.624	.632	15.85	16.05
E1	.524	.535	13.30	13.60
e	.215	BSC	5.45	BSC
H	.736	.752	18.70	19.10
L	.094	.106	2.40	2.70
L1	.047	.055	1.20	1.40
L2	.039	.045	1.00	1.15
L3	.010	BSC	0.25	BSC
L4	.150	.161	3.80	4.10

IXYS reserves the right to change limits, test conditions, and dimensions.

 IXYS MOSFETs and IGBTs are covered by 4,835,592 4,931,844 5,049,961 5,237,481 6,162,665 6,404,065 B1 6,683,344 6,727,585
 one or more of the following U.S. patents: 4,850,072 5,017,508 5,063,307 5,381,025 6,259,123 B1 6,534,343
 4,881,106 5,034,796 5,187,117 5,486,715 6,306,728 B1 6,583,505

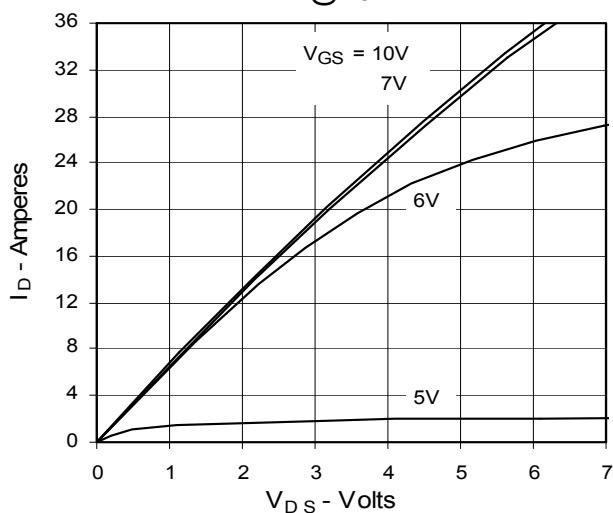
TO-247 AD (IXFH) Outline


Dim.	Millimeter Min.	Millimeter Max.	Inches Min.	Inches Max.
A	4.7	5.3	.185	.209
A ₁	2.2	2.54	.087	.102
A ₂	2.2	2.6	.059	.098
b	1.0	1.4	.040	.055
b ₁	1.65	2.13	.065	.084
b ₂	2.87	3.12	.113	.123
C	.4	.8	.016	.031
D	20.80	21.46	.819	.845
E	15.75	16.26	.610	.640
e	5.20	5.72	0.205	0.225
L	19.81	20.32	.780	.800
L1		4.50		.177
ØP	3.55	3.65	.140	.144
Q	5.89	6.40	0.232	0.252
R	4.32	5.49	.170	.216
S	6.15	BSC	242	BSC

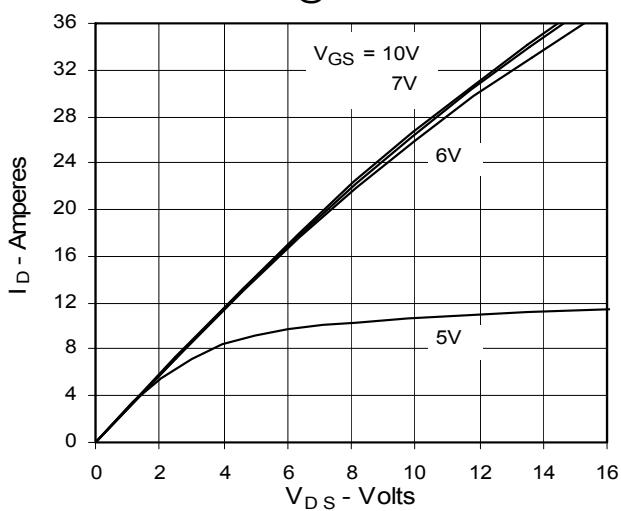
TO-264 (IXFK) Outline

 1 - GATE
 2, 4 - DRAIN (COLLECTOR)
 3 - SOURCE (EMITTER)

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.185	.209	4.70	5.31
A1	.102	.118	2.59	3.00
b	.037	.055	0.94	1.40
b1	.087	.102	2.21	2.59
b2	.110	.126	2.79	3.20
c	.017	.029	0.43	0.74
D	1.007	1.047	25.58	26.59
E	.760	.799	19.30	20.29
e	.215BSC		5.46 BSC	
J	.000	.010	0.00	0.25
K	.000	.010	0.00	0.25
L	.779	.842	19.79	21.39
L1	.087	.102	2.21	2.59
ØP	.122	.138	3.10	3.51
Q	.240	.256	6.10	6.50
Q1	.330	.346	8.38	8.79
ØR	.155	.187	3.94	4.75
ØR1	.085	.093	2.16	2.36
S	.243	.253	6.17	6.43

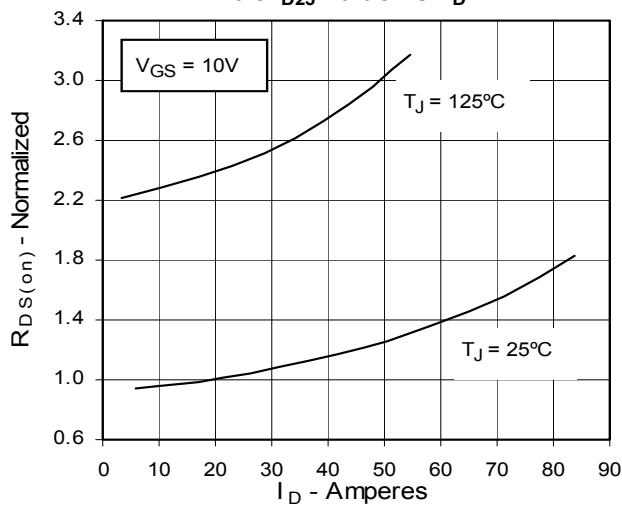
**Fig. 1. Output Characteristics
@ 25°C**



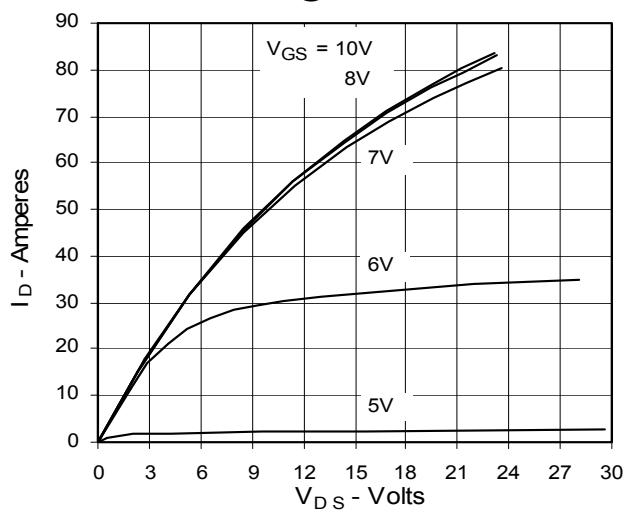
**Fig. 3. Output Characteristics
@ 125°C**



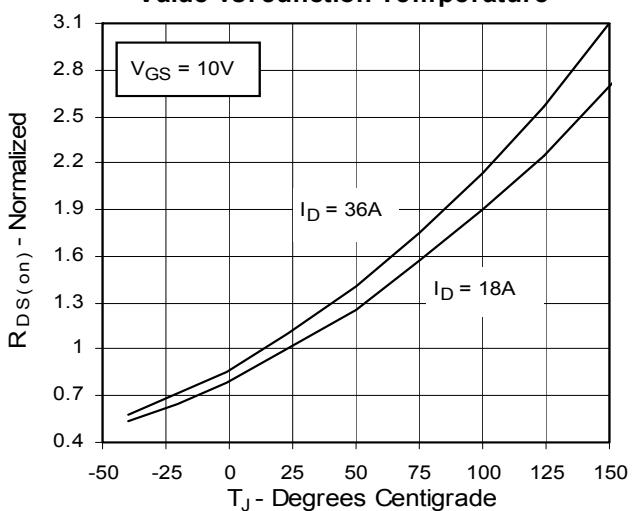
**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25}
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case
Temperature**

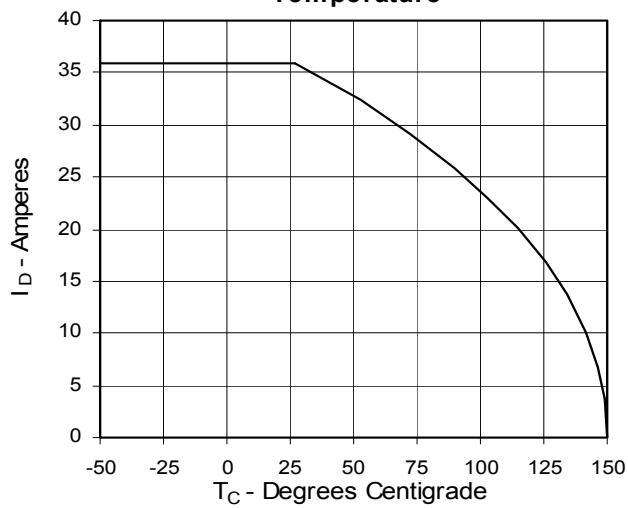
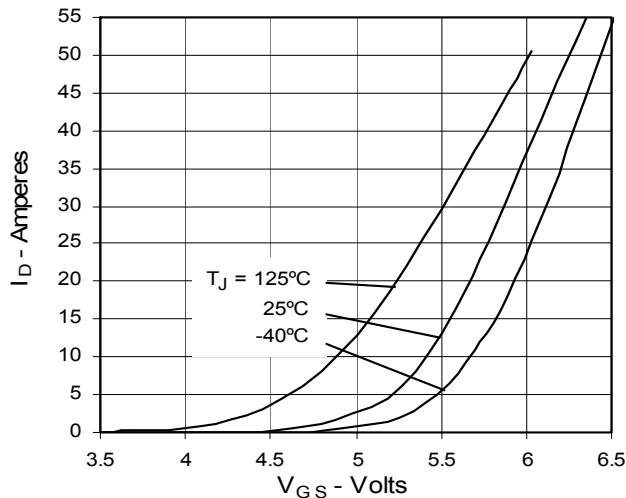
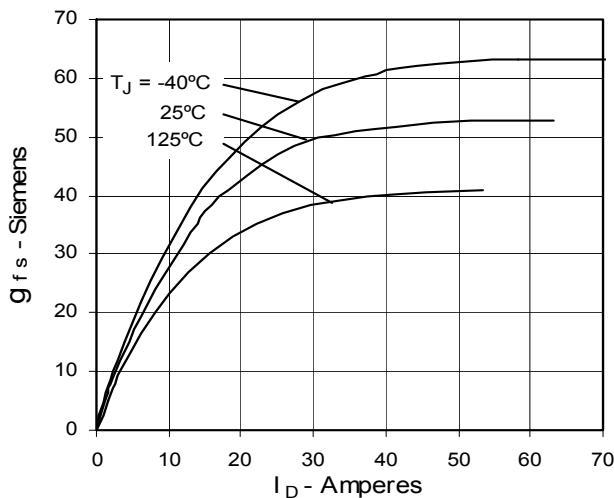
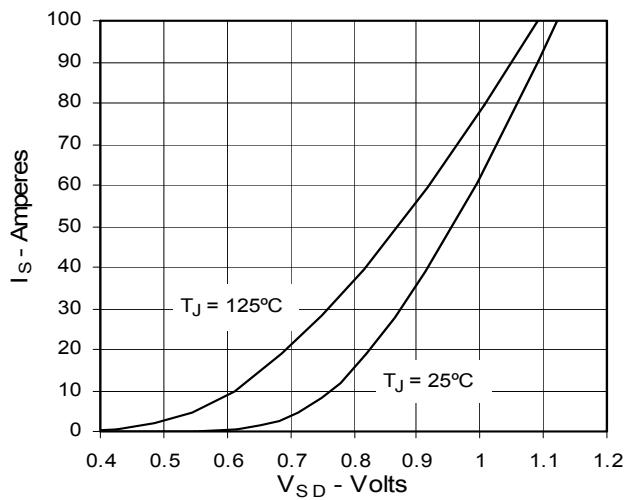
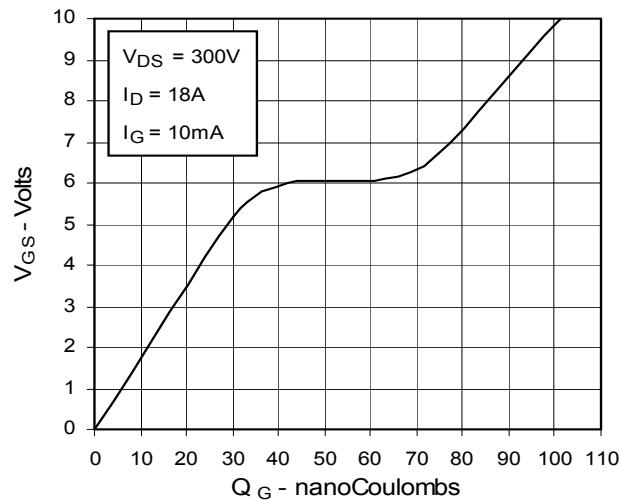
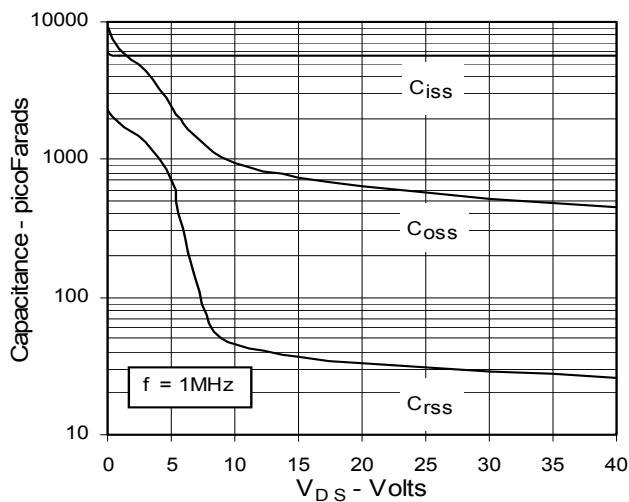


Fig. 7. Input Admittance

Fig. 8. Transconductance

**Fig. 9. Source Current vs.
Source-To-Drain Voltage**

Fig. 10. Gate Charge

Fig. 11. Capacitance

Fig. 12. Maximum Transient Thermal Resistance
